Search Notes						

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/600,711	BAYCHAR,	
Examiner	Art Unit	
Matthew D. Matzek	1771	•

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Class	Subclass	Date	Examiner
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INT	INTERFERENCE SEARCHED		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
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EAST	1/24/2005	ММ
	7/18/05	мм
PLUS	1/24/2005	мм
IDS	1/25/2005	мм
Inventor Search / ASS/GAEC	1/25/2005	MM M M